

Title:	Performance report for SiT9386, 25 MHz, HCSL		
Type:	Performance report	Rev:	1.0
Orig:		Date:	April 16, 2018

## Performance report for SiT9386 - 25 MHz, HCSL

### **Conditions:**

- Frequency 25 MHz

VDD: 2.5 V, 3.3 VRoom temperature

- Termination:

 $\circ$  30  $\Omega$  series and 50  $\Omega$  to GND.

# **Equipment:**

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, differential voltage swing, rise/fall
20 Gsps)	time, duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency

## Test setup:

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 30  $\Omega$  series and 50  $\Omega$  to GND. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 1 shows test setup diagram for waveform parameters measurement.

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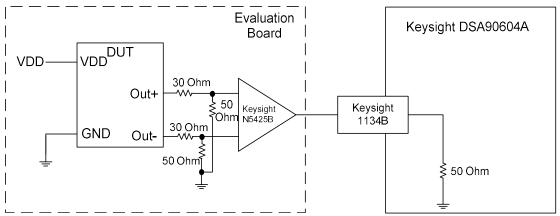


Figure 1: Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

For period jitter measurement output is terminated with 30  $\Omega$  series and 50  $\Omega$  to GND at the input of hi-speed comparator (ADCMP581). AC coupled comparator's output is connected to oscilloscope channel. Figure 2 shows test setup diagram for period jitter measurement.

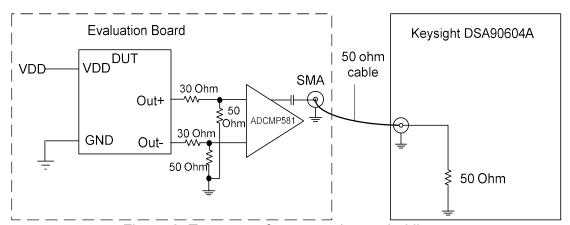
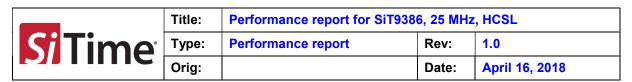


Figure 2: Test setup for measuring period jitter

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Output is also terminated with 30  $\Omega$  series at the source side. Figure 3 shows test setup diagram for phase noise measurement.



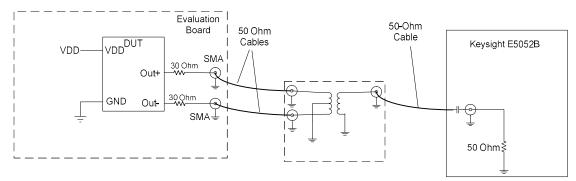


Figure 3: Test setup for measuring phase noise.

For IDD measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.

#### Data:

- Phase noise
- Integrated phase jitter
- RMS period jitter
- Peak-to-peak period jitter
- Rise/fall time
- Duty cycle
- Differential output swing
- IDC
- Frequency stability over temperature

Table 1: Summary performance data

Parameter	Units	Voltage	
Farametei	Utilis	2.5 V	3.3 V
Integrated Phase jitter (1.875 MHz - 5 MHz)	fs, rms	88	86
Integrated Phase jitter (12 kHz - 5 MHz)	fs, rms	209	207
Period jitter	ps, rms	0.98	0.96
Period jitter (10,000 cycles)	ps, pk-pk	7.62	7.51
Duty cycle	%	50.0	50.0
Rise time (20% - 80%)	ps	374	370
Fall time (80% - 20%)	ps	378	375
Differential voltage swing	V	1.33	1.40
Current consumption (no load, output enabled)	mA	74.3	75.0
Current consumption (no load, output disabled)	mA	51.4	51.9

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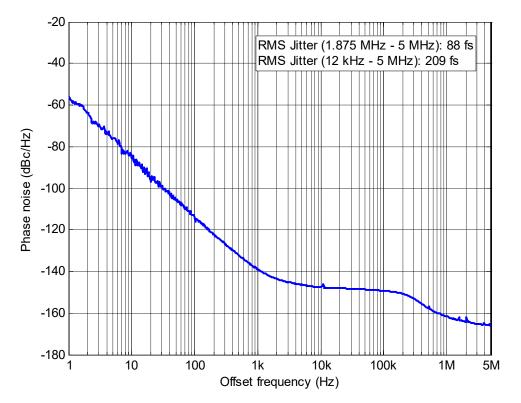


Figure 4: Phase noise, 2.5 V



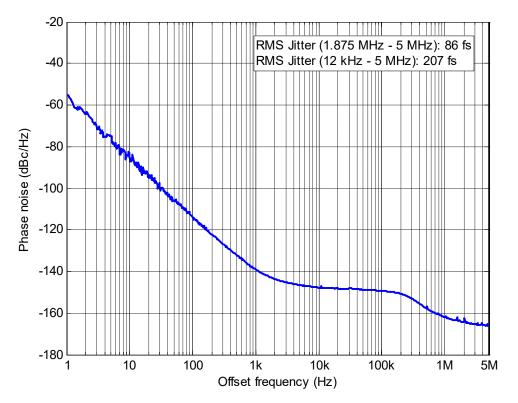


Figure 5: Phase noise, 3.3 V

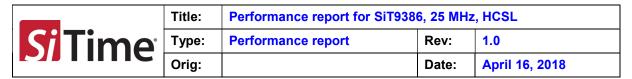




Figure 6: Output waveform, 2.5 V

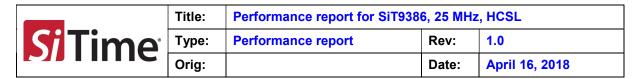




Figure 7: Output waveform, 3.3 V



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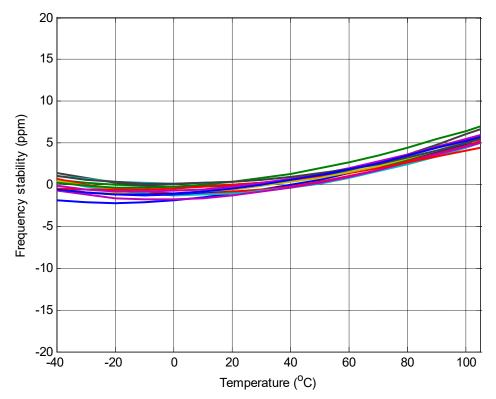


Figure 8: Frequency stability\* over temperature, 2.5 V

\*SiT9386 frequency stability is independent of output frequency.



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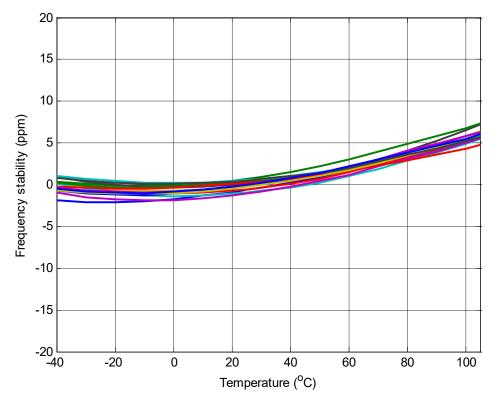


Figure 9: Frequency stability over temperature, 3.3 V